

**MONDAY 2 DECEMBER**

07.45 - 08.50	<b>REGISTRATION</b> Venue: Modlec Building	
<b>SESSION 1</b>	<b>GENERAL</b> Chair: Jaco Olivier	
08.50 - 09.00	<b>WELCOME AND OPENING REMARKS</b>	
09.00 – 09.25	Tian Olivier	Building a DIY low cost polarized light microscope for taking high quality microphotographs of home-made crystals.
<b>SESSION 2</b>	<b>BIOIMAGING</b> Chair: James Wesley-Smith	
09.25 - 10.00	Lize Engelbrecht	BIOIMAGING COMMUNITIES WITH IMPACT - IN SOUTH AFRICA, ON THE AFRICAN CONTINENT AND GLOBALLY
10.00 - 10.20	Soné Hendriks	Discover new insights through correlative microscopy
10.20 - 10.40	Ben Barkay and J.Otterstrom	High Content Imaging and Analysis System with Zebrafish Analysis
10.40 - 11.10	<b>MORNING TEA</b>	
11.10 – 11.30	Itziar Serna Martin	New Developments in Cryo-Electron Microscopy: Pushing Boundaries for Structural Determination
11.30 – 11.50	Eudri Venter	JEOL TEM solutions for life sciences, data collection made easy
11.50 – 12.10	Ben Barkay	Intravista Cellular Imaging in a Live Mouse Model
12.10 – 13.10	<b>LUNCH</b> Venue: Modlec Building	
<b>SESSION 2</b>	<b>SAMPLE PREPARATION</b> Chair: Rodney Genga	
13.10 - 13.30	Ryno Claassen	Ultramicrotome technology for state-of-the-art electron microscopy sectioning
13.30 - 13.50	Chris Botha	Using Argon Ion Milling to reduce sample preparation-induced artifacts in SEM and TEM applications
<b>SESSION 3</b>	<b>TECHNIQUES</b> Chair: Arno Janse van Vuuren	
13.50 - 14.10	Keith Dicks	Near Axis Transmission Kikuchi Diffraction

14.10 - 14.30	Damien McGrouther	Developments for automation and imaging of dose-sensitive materials on JEOL TEM/STEMs
14.30 – 14.50	Daniel Stroppa	Fast 4D STEM with ARINA Hybrid-Pixel Detector
14.50 – 15.10	Rahul Kumar	Transforming Precision Imaging - SilVIR™ detector at the core of the system, achieve much lower noise, higher sensitivity, and improved photon resolving capabilities.
15.10 – 15.40	<b>AFTERNOON TEA</b>	
<b>SESSION 3</b>	<b>INSTRUMENTATION</b> Chair: Mike Lee	
15.40 – 16.00	Reza Zamani	Tackling the challenges of novel materials analysis: recent conceptual and technological advances in transmission electron microscopy
16.00 – 16.20	Eudri Venter	JEOL FE-SEMs, making high-quality data collection available to all
16.20 – 16.40	Keith Dicks	BEX - Backscattered Electron and X-Ray Imaging – BEX & Unity real time elemental observation for SEM
17.30 - 21.00	<b>WELCOME COCKTAIL EVENT</b> Venue: Modlec Building  Sponsored by Zeiss	